

SN74LVC1G3157-Q1 Automotive Single-Pole Double-Throw Analog Switch

1 Features

- · Functional safety capable
 - Documentation available to aid functional safety system design
- AEC-Q100 qualified for automotive applications:
 - Temperature grade 1: –40°C to +125°C, T_A
- ESD protection exceeds 2000V per MIL-STD-883. method 3015; exceeds 200V using machine model (C = 200pF, R = 0)
- 1.65V to 5.5V V_{CC} operation
- Useful for analog and digital applications
- Specified break-before-make switching
- Rail-to-rail signal handling
- High degree of linearity
- High speed, typically 0.5ns $(V_{CC} = 3V, C_1 = 50pF)$
- Low ON-State resistance, typically approximately

 $(V_{CC} = 4.5V)$

Latch-up performance exceeds 100mA per JESD 78, Class II

3 Description

The SN74LVC1G3157-Q1 device is a single-pole double-throw (SPDT) analog switch designed for 1.65V to 5.5V V_{CC} operation.

The SN74LVC1G3157 device can handle analog and digital signals. The device permits signals with amplitudes of up to V_{CC} (peak) to be transmitted in either direction.

Applications include signal gating, modulation or demodulation (modem), and signal multiplexing for analog-to-digital and digital-to-analog conversion systems.

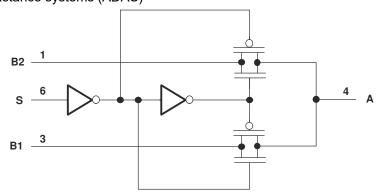
Package Information

	PART NUMBER	PACKAGE (1)	BODY SIZE (NOM)
	SN74LVC1G3157-Q1	SOT-23 (6)	2.90mm × 1.60mm
		SC70 (6)	2.00mm × 1.25mm

For all available packages, see the orderable addendum at the end of the data sheet.

2 Applications

Advanced driver assistance systems (ADAS)



Logic Diagram (Positive Logic)



Table of Contents

1 Features1	7.4 Device Functional Modes	16
2 Applications1	8 Application and Implementation	17
3 Description1	8.1 Application Information	17
4 Pin Configuration and Functions3	8.2 Typical Application	
5 Specifications4	9 Power Supply Recommendations	18
5.1 Absolute Maximum Ratings4	10 Layout	19
5.2 ESD Ratings4	10.1 Layout Guidelines	19
5.3 Recommended Operating Conditions5	10.2 Layout Example	19
5.4 Thermal Information5	11 Device and Documentation Support	20
5.5 Electrical Characteristics6	11.1 Documentation Support	20
5.6 Switching Characteristics 125C7	11.2 Receiving Notification of Documentation Updates	20
5.7 Analog Channel Specifications8	11.3 Support Resources	20
5.8 Typical Characteristics9	11.4 Trademarks	20
6 Parameter Measurement Information10	11.5 Electrostatic Discharge Caution	20
7 Detailed Description16	11.6 Glossary	20
7.1 Overview	12 Revision History	21
7.2 Functional Block Diagram16	13 Mechanical, Packaging, and Orderable	
7.3 Feature Description16	Information	21



4 Pin Configuration and Functions

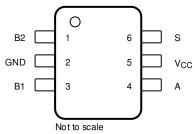


Figure 4-1. DBV Package 6-Pin SOT-23 Top View

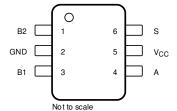


Figure 4-2. DCK Package 6-Pin SC70 Top View

Table 4-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
A	4	I/O	Common terminal
B1	3	I/O	First terminal
B2	1	I/O	Second terminal
GND	2	_	Ground
S	6	I	Select
V _{CC}	5	I	Power supply

(1) I = input, O = output, GND = ground.



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	-0.5	6	V
V _{IN}	Control input voltage ^{(2) (3)}	-0.5	V _{DD} + 0.5V	V
V _{I/O}	Voltage range applied to any output in the high-impedance or power-off state ⁽²⁾ (3) (4) (5)	-0.5	6	V
I _{IK}	Control input clamp current V _{IN} < 0	-50		mA
I _{I/O}	I/O port diode current V _{I/O} < 0 or V _{I/O} > V _{CC}	-50		mA
I _{I/O}	On-state switch current ⁽⁶⁾ V _{I/O} = 0 to V _{CC}	-128	128	mA
	Continuous current through V _{CC} or GND	-100	100	mA
T _J	Junction temperature		150	С
Storage temperature, T _{stg}		-65	150	С

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to ground unless otherwise specified.
- (3) The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 4) This value is limited to 5.5V maximum.
- (5) V_I , V_O , V_A , and V_{Bn} are used to denote specific conditions for $V_{I/O}$.
- (6) I_{I} , I_{O} , I_{A} , and I_{Bn} are used to denote specific conditions for $I_{I/O}$.

5.2 ESD Ratings

				VALUE	UNIT
	Electrostatic discharge C	Human body model (HBM), per AEC Q100-002 ⁽¹⁾ HBM ESD Classification Level 1C		±2000	V
V _(ESD)		Charged device model (CDM), per	Other pins	±1000	V
		AEC Q100-011 CDM ESD Classification Level C6	Corner pins (B2, B1, S, and A)	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification



5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	NOM MAX	UNIT
V _{CC}	Supply voltage		1.65	5.5	V
V _{I/O}	Switch input or output voltage (Max of V _{CC})		0	V _{CC}	V
V _{IN}	Control input voltage		0	5.5	V
V _{IH}	High-level input voltage, control input (0.75*V _{CC})	V _{CC} = 1.65V to 1.95V	V _{CC} × 0.75		V
V _{IH}	High-level input voltage, control input (0.7*V _{CC})	V _{CC} = 2.3V to 5.5V	V _{CC} × 0.7		V
V _{IL}	Low-level input voltage, control input (0.25*V _{CC})	V _{CC} = 1.65V to 1.95V		V _{CC} × 0.25	V
V _{IL}	Low-level input voltage, control input (0.3*V _{CC})	V _{CC} = 2.3V to 5.5V		V _{CC} × 0.3	V
		V _{CC} = 1.8 ± 0.15V		20	
dt/dv	Input transition rise or fall rate	$V_{CC} = 2.5 \pm 0.2 V$		20	ns/V
ai/av	Input transition rise or fall rate	$V_{CC} = 3.3V \pm 0.3V$		10	TIS/ V
		$V_{CC} = 5V \pm 0.5V$		10	
T _A			-40	125	°C

⁽¹⁾ All unused inputs of the device must be held a V_{CC} or GND to ensure proper device operation. Refer to the *Implications of Slow or Floating CMOS Inputs* application note.

5.4 Thermal Information

		SN74LVC1	SN74LVC1G3157-Q1			
	THERMAL METRIC ⁽¹⁾	DBV (SOT23)	DCK (SC70)	UNIT		
		6 PINS	6 PINS			
R _{0JA}	Junction-to-ambient thermal resistance	258.2	286.4	°C/W		
R _{0JC(top)}	Junction-to-case (top) thermal resistance	182.8	224.6	°C/W		
R _{0JB}	Junction-to-board thermal resistance	142.8	143.7	°C/W		
Ψ_{JT}	Junction-to-top characterization parameter	118.4	124.5	°C/W		
Ψ_{JB}	Junction-to-board characterization parameter	142.2	142.8	°C/W		

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application note.



5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TES	T CONDITIONS	3	V _{cc}	MIN TYP(1)	MAX	UNIT
				V _I = 0V,	I _O = 4mA	4.05)/	11	20	
				V _I = 1.65V,	I _O = -4mA	1.65V	15	50	
				V _I = 0V,	I _O = 8mA	2.2)/	8	12	
				V _I = 2.3V,	I _O = -8mA	2.3V	11	30	
r _{on}	ON-state switch resistance	2 (2)	See Figure 6-1 and Figure 5-1	V _I = 0V,	I _O = 24mA	3V	7	9.5	Ω
			and rigure or	V _I = 3V,	I _O = -24mA	3 V	9	20	
				V _I = 0V,	I _O = 30mA		6	7.5	
				V _I = 2.4V,	$I_{O} = -30 \text{mA}$	4.5V	7	12	
				V _I = 4.5 ,	I _O = -30mA		7	15	
					I _A = -4mA	1.65V		200	
_	ON-state switch resistance	Э	$0 \le V_{Bn} \le V_{CC}$		$I_A = -8mA$	2.3V		75	Ω
r _{range}	over signal range ^{(2) (3)}		(see Figure 6-1 and	d Figure 5-1)	$I_A = -24mA$	3V		25	12
					$I_A = -30 \text{mA}$	4.5V		15	
	Difference in on-state resistance between switches ⁽²⁾ (4) (5)			V _{Bn} = 1.15V,	I _A = -4mA	1.65V	0.5		Ω
۸r			See Figure 6-1	V _{Bn} = 1.6V,	I _A = -8mA	2.3V	0.1		
∆r _{on}			See Figure 0-1	V _{Bn} = 2.1V,	I _A = -24mA	3V	0.1		12
				V _{Bn} = 3.15V,	$I_A = -30 \text{mA}$	4.5V	0.1		
				I _A = -4mA			110		
 -	ON-state resistance flatne	ss ⁽²⁾	0 ≤ V _{Bn} ≤ V _{CC}		$I_A = -8mA$	2.3V	26		Ω
r _{on(flat)}	(4) (6)	(4) (6)		O = VBn = VCC		3V	9		1 12
			I _A :		$I_A = -30 \text{mA}$	4.5V	4		
I _{off} (7)	OFF-state switch leakage		$0 \le V_I, V_O \le V_{CC}$ (s	ee Figure 6-2)		1.65V		±1	μA
off `	current		0 = v , v0 = vcc (s	ee rigule 0-2)		to 5.5V	±0.05	±1 ⁽¹⁾	μΛ
1	ON-state switch leakage c	urrent	V. = V or GND \	/ Open (see	Figure 6-3)	5.5V		±1	μA
I _{S(on)}	ON-State Switch leakage C	unent	VI - VCC OI GIVD, V	70 - Open (see	rigure 0-3)	J.5V		±0.1 ⁽¹⁾	μΛ
1	Control input current	atral in suit summer.		0V		±1	μA		
I _{IN}	IN Control input current		$0 \le V_{IN} \le V_{CC}$			to 5.5V	±0.05	±1 ⁽¹⁾	μΑ
I _{CC}	Supply current		$V_{IN} = V_{CC}$ or GND			5.5V	1	10	μΑ
ΔI _{CC}	Supply-current change		$V_{IN} = V_{CC} - 0.6V$			5.5V		500	μA
C _{in}	Control input capacitance	S				5V	2.7		pF
C _{io(off)}	Switch I/O capacitance	Bn				5V	5.2		pF
Corre	Switch I/O capacitance	Bn				5V	17.3		הר
C _{io(on)}	Switch i/O capacitance	Α				υν	17.3		pF

⁽¹⁾ $T_A = 25^{\circ}C$

⁽²⁾ Measured by the voltage drop between I/O pins at the indicated current through the switch. ON-state resistance is determined by the lower of the voltages on the two (A or B) ports.

⁽³⁾ Specified by design

Δr_{on} = r_{on(max)} - r_{on(min)} measured at identical V_{CC}, temperature, and voltage levels
 This parameter is characterized, but not tested in production.

Flatness is defined as the difference between the maximum and minimum values of ON-state resistance over the specified range of (6) conditions.

I_{off} is the same as I_{S(off)} (OFF-state switch leakage current).



5.6 Switching Characteristics 125C

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	FROM (INPUT)	то (оитрит)	V _{cc}	MIN	NOM MAX	UNIT
				1.8V ± 0.15V		2	
t _{pd} ⁽¹⁾	$R_L = 250\Omega$, $C_L = 50pF$, $V_{load} = V_{CC}$	A or Bn	Bn or A	2.5V ± 0.2V		1.2	ns
pd `	N _L = 230Ω, O _L = 30βr, V _{load} = V _{CC}	A OI BII	BITOLA	3.3V ± 0.3V		0.8	
				5V ± 0.5V		0.5	
				1.8V ± 0.15V	5	24	
t _{en} ⁽²⁾	$R_L = 250\Omega$, $C_L = 50pF$, $V_{load} = V_{CC}$			2.5V ± 0.2V	3.5	14	
len (-)		- S		3.3V ± 0.3V	2.5	8	
			Bn	5V ± 0.5V	1.7	7	
	$R_L = 250\Omega$, $C_L = 50pF$, $V_{load} = V_{CC}$, $V_{\Delta} =$		ы	1.8V ± 0.15V	3	13	ns
t _{dis} (3)				2.5V ± 0.2V	2	7.5	
ldis (°)	0.3V			3.3V ± 0.3V	1.5	6.5	
				5V ± 0.5V	0.8	5	
				1.8V ± 0.15V	0.5		
T (4)	Brook before make time			2.5V ± 0.2V	0.5]
T _{B-M} ⁽⁴⁾	Break before make time			3.3V ± 0.3V	0.5		ns
				5V ± 0.5V	0.5		

⁽¹⁾ t_{pd} is the slower of t_{PLH} or t_{PHL} . The propagation delay is calculated RC time constant of the typical ON-state resistance of the switch and the specified load capacitance when driven by an ideal voltage source (zero output impednace).

Copyright © 2025 Texas Instruments Incorporated

Submit Document Feedback

 t_{en} is the slower of t_{PZL} or t_{PZH} .

 ⁽³⁾ t_{dis} is the slower of t_{PLZ} or t_{PHZ}.
 (4) Specified by design



5.7 Analog Channel Specifications

over operating free-air temperature range (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V _{cc}	MIN NOM	MAX	UNIT
				1.65V	300		
Frequency	A or Bn	Bn or A	D = 500 f = sine ways	2.3V	300		MHz
response (switch on) ⁽¹⁾	AOIDII	BII OF A	$R_L = 50\Omega$, $f_{in} = sine wave$	3V	300		IVITZ
,				4.5V	300		
				1.65V	-54		
Crosstalk	B1 or B2	D2 or D4	$R_L = 50\Omega$, $f_{i,n} = 10MHz$	2.3V	-54		dB
(between switches) ⁽²⁾	BT OF BZ	B2 or B1	(sine wave)	3V	-54		uБ
,				4.5V	-54		
				1.65V	-57		
Feed through	A or Bn	Bn or A	$C_L = 5pF, R_L = 50\Omega, f_{in} =$	2.3V	-57		dB
attenuation (switch off)(2)				3V	-57		
,				4.5V	-57		
Channa inia atian	C ()/a = \/DD/()		0 = 0.4 = F D = 4M0	3.3V	3		0
Charge injection	S (Vs = VDD/2)	A	$C_L = 0.1 \text{nF}, R_L = 1 \text{M}\Omega$	5V	7		рС
			V_l = 1.4 V_{p-p} , Vbias = Vcc/2, R_L = 10k Ω , f_{in} = 600Hz to 20kHz (sine wave)	1.65V	0.5		
Total harmonic	A or Dr	Dr. or A	V_l = 2.0 V_{p-p} , Vbias = Vcc/2, R_L = 10k Ω , f_{in} = 600 Hz to 20kHz (sine wave)	2.3V	0.025		1
distortion	A OI BII	Vcc/2, R _L = 1	V_{l} = 2.5 V_{p-p} , Vbias = Vcc/2, R_{L} = 10 $k\Omega$, f_{in} = 600 Hz to 20 k Hz (sine wave)	3V	0.015		%
		V_{l} = 4.0 V_{p-p} , Vbias Vcc/2, R_{L} = 10k Ω , f = 600Hz to 20kHz (wave)		4.5V	0.01		

⁽¹⁾ Set fin to 0dBm and provide a bias of 0.4V. Increase fin frequency until the gain is 3dB below the insertion loss.

⁽²⁾ Set fin to 0dBm and provide a bias of 0.4V.



5.8 Typical Characteristics

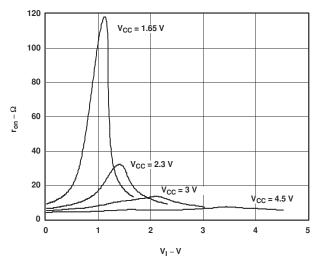


Figure 5-1. Typical R_{on} as a Function of Input Voltage (V_I) for V_{I} = 0 To V_{CC}



6 Parameter Measurement Information

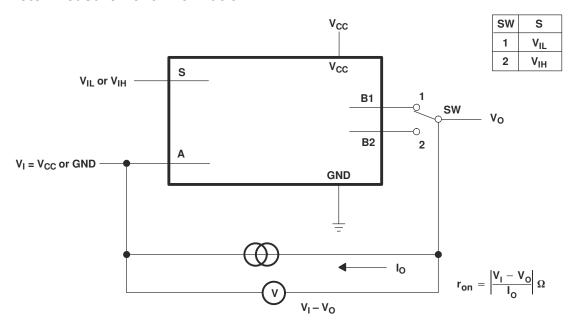
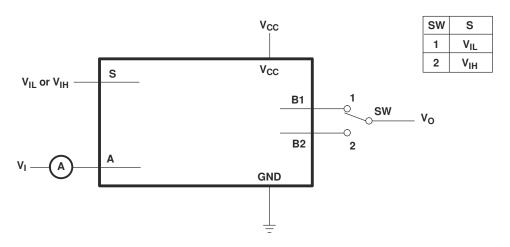


Figure 6-1. ON-State Resistance Test Circuit



 $\begin{array}{l} \text{Condition 1: V}_{I} = \text{GND, V}_{O} = \text{V}_{CC} \\ \text{Condition 2: V}_{I} = \text{V}_{CC}, \text{V}_{O} = \text{GND} \\ \end{array}$

Figure 6-2. OFF-State Switch Leakage-Current Test Circuit



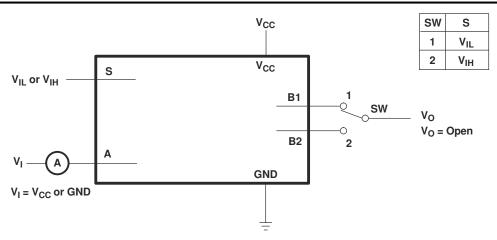
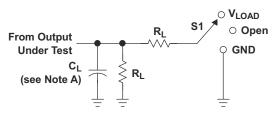


Figure 6-3. ON-State Switch Leakage-Current Test Circuit

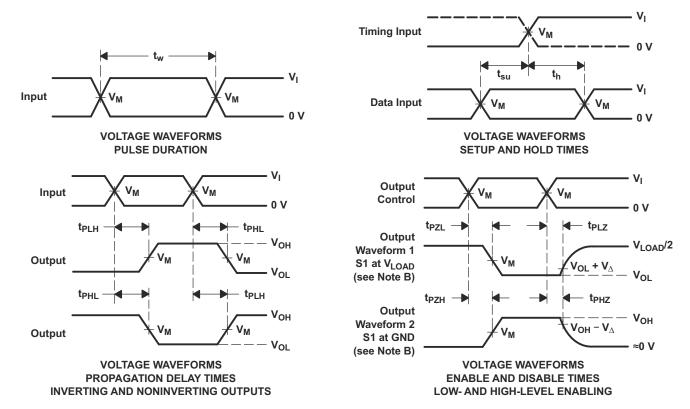




TEST	S1
t _{PLH} /t _{PHL}	Open
t_{PLZ}/t_{PZL}	V _{LOAD}
t _{PHZ} /t _{PZH}	GND

LOAD CIRCUIT

V	INPUTS		V	V		Б	V
V _{CC}	VI	t _r /t _f	V _M	V _{LOAD}	CL	R_L	$V_{\!\scriptscriptstyle \Delta}$
1.8 V \pm 0.15 V	V _{CC}	≤2 ns	V _{CC} /2	2 × V _{CC}	50 pF	500 Ω	0.3 V
2.5 V \pm 0.2 V	V _{CC}	≤2 ns	V _{CC} /2	2 × V _{CC}	50 pF	500 Ω	0.3 V
3.3 V \pm 0.3 V	V _{CC}	≤2.5 ns	V _{CC} /2	2 × V _{CC}	50 pF	500 Ω	0.3 V
5 V \pm 0.5 V	V _{CC}	≤2.5 ns	V _{CC} /2	2 × V _{CC}	50 pF	500 Ω	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10-MHz, Z_0 = 50 Ω .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

Figure 6-4. Load Circuit and Voltage Waveforms



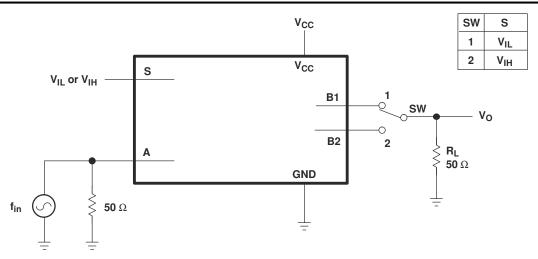


Figure 6-5. Frequency Response (Switch On)

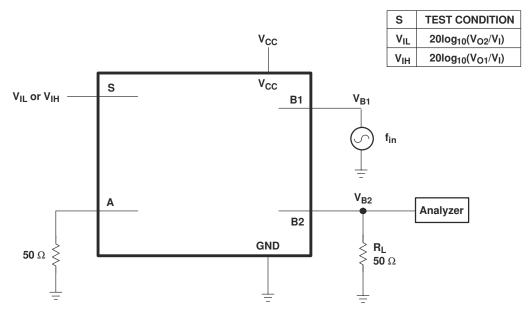


Figure 6-6. Crosstalk (Between Switches)

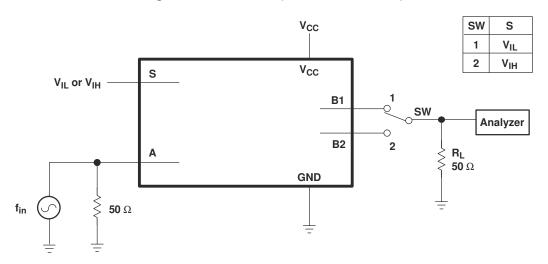


Figure 6-7. Feedthrough



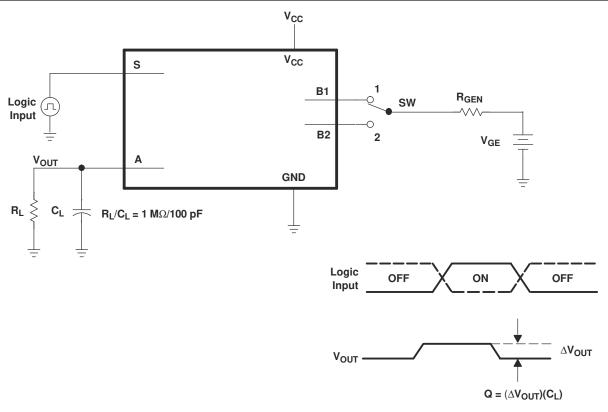


Figure 6-8. Charge-Injection Test

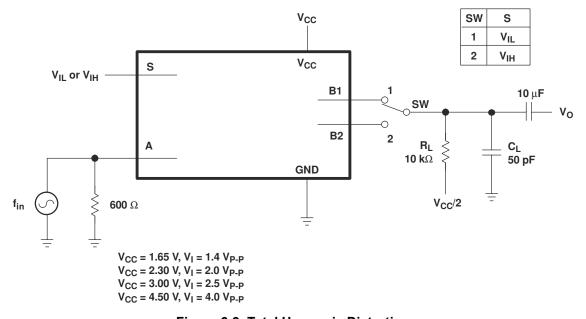


Figure 6-9. Total Harmonic Distortion

Submit Document Feedback

Copyright © 2025 Texas Instruments Incorporated



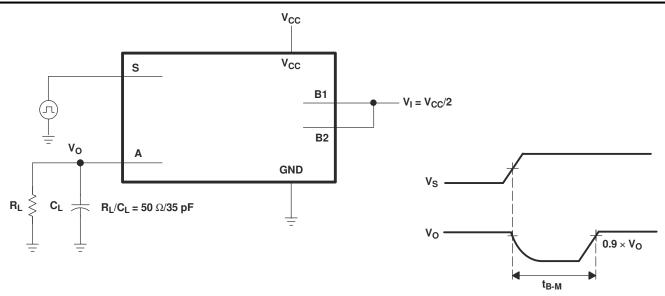


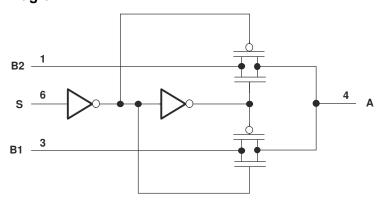
Figure 6-10. Break-Before-Make Internal Timing

7 Detailed Description

7.1 Overview

The SN74LVC1G3157-Q1 device is a single-pole double-throw (SPDT) analog switch designed for 1.65V to 5.5V V_{CC} operation. The SN74LVC1G3157-Q1 device can handle analog and digital signals. The device permits signals with amplitudes of up to V_{CC} (peak) to be transmitted in either direction.

7.2 Functional Block Diagram



Logic Diagram (Positive Logic)

7.3 Feature Description

These devices are qualified for automotive applications. The 1.65V to 5.5V supply operation allows the device to function in many different systems comprised of different logic levels, allowing rail-to-rail signal switching. Either the B1 channel or the B2 channel is activated depending upon the control input. If the control input is low, B1 channel is selected. If the control input is high, B2 channel is selected.

7.4 Device Functional Modes

Table 7-1 lists the ON channel when one of the control inputs is selected.

Table 7-1. Function Table

CONTROL INPUTS	ON CHANNEL				
L	B1				
Н	B2				



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74LVC1G3157-Q1 SPDT analog switch is flexible enough for use in a variety of circuits such as analog audio routing, power-up monitor, memory sharing and so on. For details on the applications, you can also view the SN74LVC1G3157 and SN74LVC2G53 SPDT Analog Switches product overview.

8.2 Typical Application

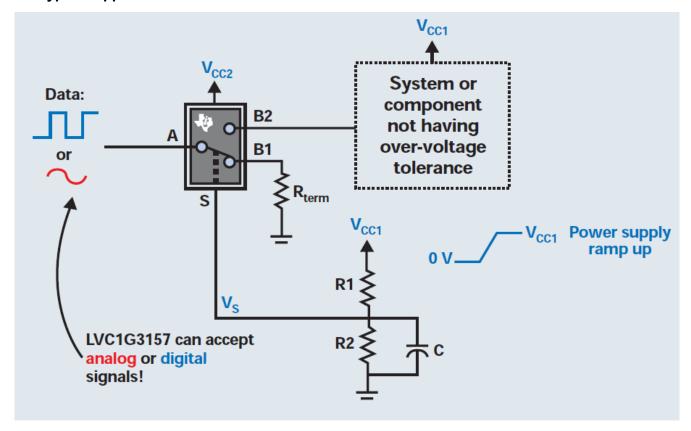


Figure 8-1. Typical Application Schematic

8.2.1 Design Requirements

The inputs can be analog or digital, but TI recommends waiting until VCC has ramped to a level in *Section 5.3* before applying any signals. Appropriate termination resistors should be used depending on the type of signal and specification. The Select pin should not be left floating; either pull up or pull down with a resistor that can be overdriven by a GPIO.

8.2.2 Detailed Design Procedure

Using this circuit idea, a system designer can ensure a component or subsystem power has ramped up before allowing signals to be applied to its input. This is useful for integrated circuits that do not have overvoltage tolerant inputs. The basic idea uses a resistor divider on the VCC1 power rail, which is ramping up. The RC time constant of the resistor divider further delays the voltage ramp on the select pin of the SPDT bus switch. By carefully selecting values for R1, R2 and C, it is possible to ensure that VCC1 will reach its nominal value before the path from A to B2 is established, thus preventing a signal being present on an I/O before the device/ system is powered up. To ensure the minimum desired delay is achieved, the designer should use Equation 1 to calculate the time required from a transition from ground (0V) to half the supply voltage (VCC1/2).

$$Set\left(\frac{R2}{R1+R2} \times VCC1 > VIH\right) of the select pin$$
(1)

Choose Rs and C to achieve the desired delay.

When Vs goes high, the signal will be passed.

8.2.3 Application Curve

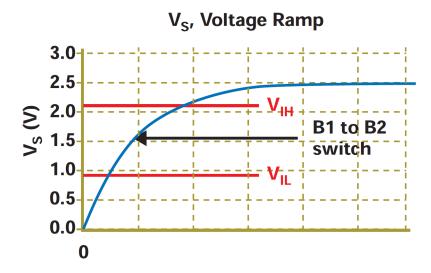


Figure 8-2. V_S Voltage Ramp

9 Power Supply Recommendations

Most systems have a common 3.3V or 5V rail that can supply the V_{CC} pin of this device. If this is not available, a Switch-Mode-Power-Supply (SMPS) or a Linear Dropout Regulator (LDO) can be used to provide supply to this device from another voltage rail.



10 Layout

10.1 Layout Guidelines

TI recommends keeping signal lines as short as possible. TI also recommends incorporating microstrip or stripline techniques when signal lines are greater than 1 inch in length. These traces must be designed with a characteristic impedance of either 50Ω or 75Ω , as required by the application. Do not place this device too close to high-voltage switching components, as they may interfere with the device.

10.2 Layout Example

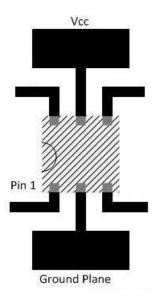


Figure 10-1. Recommended Layout Example



11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, SN74LVC1G3157 and SN74LVC2G53 SPDT Analog Switches product overview
- Texas Instruments, SN74LVC1G3157-Q1 Functional Safety, FIT Rate, FMD, and Pin FMA report

11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

11.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.



12 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision H (December 2021) to Revision I (June 2025)	Page
Changed ABS max V _{CC} and V _{I/O} voltage	4
Updated thermal parameters for DBV and DCK	<mark>5</mark>
Updated r _{range}	<mark>6</mark>
Changed enable timing for minimum 1.8V, and maximum 3.3V and 5V	7
Changed disable timing for maximum 3.3V and 5V	7
Changed THD at 1.65V r _{range}	8
Changes from Revision G (April 2019) to Revision H (December 2021)	Page
• Updated the numbering format for tables, figures, and cross-references throughout the documen	t 1
Added functional safety text to the data sheet	
Changes from Revision F (March 2015) to Revision G (April 2019)	Page
Changed the automotive Features	1
Changed the Pin Configuration images	
Changes from Revision E (April 2008) to Revision F (March 2015)	Page
 Added ESD Ratings table, Feature Description section, Device Functional Modes, Application an Implementation section, Power Supply Recommendations section, Layout section, Device and 	d
Documentation Support section, and Mechanical, Packaging, and Orderable Information section	1
, , , , , , , , , , , , , , , , , , , ,	

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Copyright © 2025 Texas Instruments Incorporated

Submit Document Feedback

www.ti.com 7-Oct-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
	()	()			(-)	(4)	(5)		(-,
1P1G3157QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CC5O
1P1G3157QDBVRQ1.A	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CC5O
1P1G3157QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	CC5O
1P1G3157QDCKRQ1	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	(C5J, C5O)
1P1G3157QDCKRQ1.A	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(C5J, C5O)
1P1G3157QDCKRQ1.B	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(C5J, C5O)

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 7-Oct-2025

OTHER QUALIFIED VERSIONS OF SN74LVC1G3157-Q1:

● Catalog : SN74LVC1G3157

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 17-Jul-2025

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
1P1G3157QDBVRQ1	SOT-23	DBV	6	3000	179.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
1P1G3157QDCKRQ1	SC70	DCK	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3

www.ti.com 17-Jul-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
1P1G3157QDBVRQ1	SOT-23	DBV	6	3000	200.0	183.0	25.0
1P1G3157QDCKRQ1	SC70	DCK	6	3000	180.0	180.0	18.0





NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

 4. Falls within JEDEC MO-203 variation AB.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025. Texas Instruments Incorporated